Special Issue

Recent Advances and Future Challenges in Manufacturing Metrology

Message from the Guest Editors

The improvement in the quality of production processes for machine and equipment parts is closely linked to advancements in the methods and tools used to control and inspect manufactured products. The foundation of such knowledge is research and, inherently, measurement in the broadest sense. Modern industry requires simple, user-friendly devices capable of delivering rapid measurements, often in real time during processing, without compromising accuracy. To meet this growing demand, manufacturers are increasingly focusing on automated production process control systems in many cases supported by AI. The successful implementation of such systems depends primarily on the reliability and comprehensiveness of monitoring technologies; that is, the availability of accurate measurement data throughout the manufacturing process. As part of Industry 4.0, modern industry expects to significantly streamline measurement processes. This involves both minimizing human errors and maximizing the quantity and quality of information obtained about product characteristics, which is often gathered simultaneously from multiple, reliable sources. We invite contributions to this Special Issue.

Guest Editors

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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